

# LZ93 Series CMOS Gate Array

## ■ Description

The LZ93 series CMOS gate array provides 300 to 5000 gates of line up with high speed and low power consumption.

It is fabricated using 1.6 $\mu$ m CMOS silicon gate/double metal technology.

## ■ Features

1. CMOS process
2. Number of gates : 300, 600, 1000, 1100, 1600, 2200, 3000, 4000, 5000
3. Internal gate delay : 1.7ns/gate
4. Macro cell : 95 cells  
74LS cell : 126 cells
5. I/O level : CMOS/TTL compatible
6. Supply voltage : 5V  $\pm$  5% (TTL interface)  
5V  $\pm$  10% (CMOS interface)



## ■ Line Up

Parameter	LZ93300	LZ93600	LZ931000	LZ931100	LZ931600	LZ932200	LZ933600	LZ934000	LZ935000
Gate count (2 input NAND conversion)	300	600	1010	1111	1596	2240	3145	4009	5000
I/O buffer count	37	51	67	77	97	97	112	128	140
Pin count	40	54	70	80	100	100	120	136	150
Process	1.6 $\mu$ m CMOS silicon gate, double metal								
Delay time	Internal gate	1.7ns/gate (F.O.=3, Wiring length : 2mm)							
	Input buffer	TTL level : 2.4ns/CMOS level : 2.9ns (F.O.=3, Wiring length : 2mm)							
	Output buffer	4.0ns (C <sub>L</sub> =20pF)							
I/O level	TTL level/CMOS level								
Supply voltage	5V $\pm$ 5% (TTL interface)/5V $\pm$ 10% (CMOS interface)								

# LZ95 Series CMOS Gate Array

## ■ Description

The LZ95 series CMOS gate array provides 2000 to 10000 gates of line up with 1.2ns/gate of delay time.

It is fabricated using the latest 1.2  $\mu$ m CMOS silicon gate, double metal technology.

## ■ Features

1. CMOS process
2. Number of gates : 300, 650, 1170, 2000, 4000, 6000, 8000, and 10000
3. Internal gate delay : 1.2ns/gate
4. Macro cell : 95 cells  
74LS cell : 126 cells
5. I/O level : CMOS/TTL level
6. Supply voltage : 5V  $\pm$  5% (TTL interface)  
5V  $\pm$  10% (CMOS interface)

## ■ Line Up

Parameter	LZ95300	LZ95650	LZ951170	LZ952000	LZ954000	LZ956000	LZ958000	LZ9510000
Gate count	315	650	1170	2000	4255	6075	8370	10032
I/O buffer count	46	62	77	97	128	148	176	194
Pin count	48	64	80	100	136	156	184	202
Process	1.2 $\mu$ m CMOS silicon gate, double metal							
Delay time	Internal gate	1.2ns/gate (F.O. = 3, Wiring length : 2mm)						
	Input buffer	TTL level : 2.4ns/CMOS level : 2.0ns (F.O. = 3, Wiring length : 2mm)						
	Output buffer	TTL level : 4.0ns/CMOS level : 4.2ns ( $C_L = 20$ pF)						
I/O level	TTL level/CMOS level							
Supply voltage	5V $\pm$ 5% (TTL interface) / 5V $\pm$ 10% (CMOS interface)							

### ■ Absolute Maximum Ratings

Parameter	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	-0.3 to +7	V
Input voltage	$V_I$	-0.3 to $V_{CC}+0.3$	V
Output voltage	$V_O$	-0.3 to $V_{CC}+0.3$	V
Operating temperature	$T_{opr}$	-10 to +70	°C
Storage temperature	$T_{stg}$	-55 to +150	°C

### ■ Recommended Operating Conditions

Parameter	Symbol	TTL level			CMOS level			Unit
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Supply voltage	$V_{CC}$	4.75	5	5.25	4.5	5	5.5	V
Operating temperature	$T_{opr}$	-10		+70	-10		+70	°C

### ■ Electrical Characteristics (Ta = -10 to +70°C, $V_{CC}=5V \pm 5%$ (TTL level), $V_{CC}=5V \pm 10%$ (CMOS level))

Parameter	Symbol	Conditions	TTL level			CMOS level			Unit	Note
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
Input "Low" current	$V_{IL}$				0.8			1.5	V	
Input "High" voltage	$V_{IH}$		2.0			3.5			V	
Input "High" threshold voltage	$V_{T+}$				2.2			3.7	V	
Input "Low" threshold voltage	$V_{T-}$	Schmitt input buffer 1	0.5			1.0			V	1
Hysteresis voltage	$V_H$		0.2			0.4			V	
Input "High" threshold voltage	$V_{T+}$						4.3		V	
Input "Low" threshold voltage	$V_{T-}$	Schmitt input buffer 2				0.8			V	2
Hysteresis voltage	$V_H$					0.6			V	
Input "High" threshold voltage	$V_{T+}$						4.5		V	
Input "Low" threshold voltage	$V_{T-}$	Schmitt input buffer 3				0.7			V	2
Hysteresis voltage	$V_H$					0.8			V	
Input "High" threshold voltage	$V_{T+}$						4.7		V	
Input "Low" threshold voltage	$V_{T-}$	Schmitt input buffer 4				0.6			V	2
Hysteresis voltage	$V_H$					1.0			V	
Output "Low" voltage	$V_{OL}$	$I_{OL} = 4mA$			0.4			0.4	V	
Output "High" voltage	$V_{OH}$	$I_{OH} = -2mA$	2.4			4.0			V	
Input leakage current	$I_{IL}$	$V_I = 0V$ to $V_{CC}$	-10		10	-10		10	μA	
Output leakage current	$I_{OZ}$	High impedance state	-10		10	-10		10	μA	

Note 1 : Applied to the input buffer cells IBFS and IBFCS for models excepting the LZ931100 and the LZ931600.

Note 2 : Applied to the schmitt trigger input buffer composed of the input buffer transferring the input potential to the interior and internal gates for both LZ93 series and LZ95 series.

